Figure 1

METHOD OF DETERMINING OVERLAY TOLERANCE
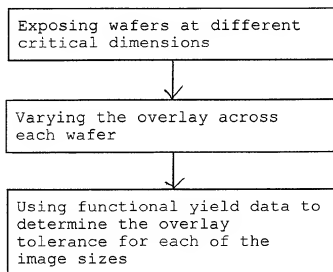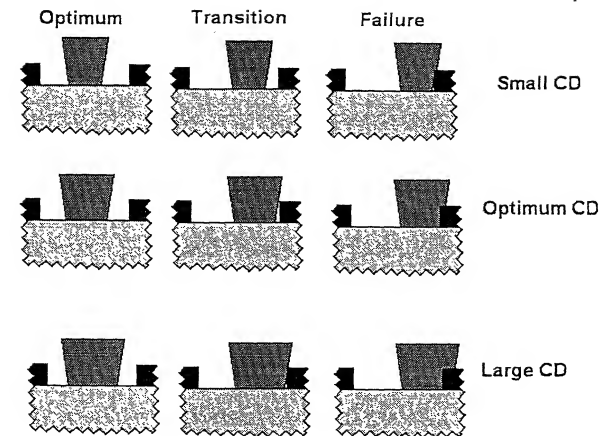
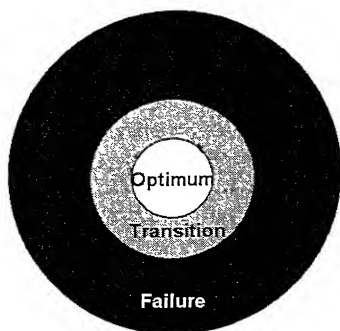Exposing wafers at different
critical dimensions

Varying the overlay across
each wafer

Using functional yield data to
determine the overlay
tolerance for each of the
image sizes

Figure 2

Figure 3